Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination
10/774,607	NAKAI, SHINYA
Examiner	Art Unit

2618

Tuan A. Tran

SEARCHED					
Class	Subclass	Date	Examiner		
455	78-83	8/30/2007	тт		
455	73,550.1				
455	552.1				
455	553.1				
455	575.1,7				
455	90.1-3				
333	100-104				
333	134,175				
370	275,278				
370	290-291				
370	286,297				
370	246,172				
370	185				
257	728,760				

TMI	INTERFERENCE SEARCHED					
Class	Subclass	Date	Examiner			
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SEARCH NOT (INCLUDING SEARCH		)
	DATE	EXMR
EAST (USPAT, USPGPUB, USOCR, FPRS, JPO, EPO, DERWENT)	11/10/2006	тт
EAST (USPAT, USPGPUB, USOCR, FPRS, JPO, EPO, DERWENT) Updating search	12/12/2006	π
Consulted with Cong Le	12/12/2006	TT
EAST (USPAT, USPGPUB, USOCR, FPRS, JPO, EPO, DERWENT) Updating search	8/30/2007	тт
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